Front-End and Readout Electronics for Silicon Trackers at the ILC

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Summary

Silicon Tracker Asynchronous events Data taking/pre-processing Occupancy: a few 100m², a few 10⁶ strips

- ~ 1 ms
- ~ 200 ms
- < 1 % in most parts
- of the detector

<u>Goals:</u>

Low noise preamplifiers Shaping times 500ns - 5µs (Strip length dependent) Analog sampling Highly shared ADC Sparsification Very low power dissipation Power cycling Compact and transparent Choice of DSµE SiGe under consideration for VFE analog

Front-end processing



Charge 1-50 MIP, S/N~15-20

Technologies

- Deep Sub-Micron CMOS UMC 0.18 μm
- SiGe envisaged for analog section

Analog Pulse Sampling Front-end under evaluation Very preliminary ideas



Silicon area and power dissipation investigated

Analog storage, digitization and sparse readout



Analog sampling after each local event Digitization after each train

Triggered readout ?





Shorter pipeline length By how much ? To be evaluated

Increased deadtime ? To be evaluated

Analog sampling on each local event Sparse readout after each trigger

Required/Expected Performance

Noise, gain: - Preamp + Shaper @ 3 µs shaping time, 50 pF detector simulated ENC 920 e- 85 e- + 16.5 e-/pF Gain 8mV/MIP over 1-75 MIP Power: - Preamp + Shaper + Analog Sampler Preamp: 70 μ W Shaper: 110 μ W Analog sampler 200 μ W ? - Shared ADC/TDC ADC: 10 bits, 2-3 μ s, 110 μ W 300 + 200 μW / channel Total: Power Switching:

If Analog + ADC are running during collisions only:e.g.1.2/100 duty cycle and $5 \ 10^6$ channels, then:Total: $500 \ 10^{-6} \ x \ 5 \ 10^6 \ x \ 1.2/100 = 30 \ Watts$

Noise (Simulations)



Consider Silicon-Germanium technology as faster/less noisy alternative

Overall Noise

Detector + FET Leakage: $N_{leak} = e/q \operatorname{sqrt}(q I \tau/4)$

Bias resistor:

$$N_{bias} = e/q \ sqrt(\tau \ kT/2R)$$

$$N_{tot}^2 = N_{fet}^2 + N_{leak}^2 + N_{bias}^2$$

 N_{fet} = 910 electrons N_{leak} = 588 electrons N_{bias} = 423 electrons

 N_{tot} = 1163 electrons

Preamp Power Switching (reminder)

- Reset the feedback capacitor after switching on and before switching off (Takes 5 us)

- Open and close two switches feeding Vdd Vss (Ron~=100 Ω) Power is zero when switched off



Prototype chip received February 28th



- Two blocks of 1.6 x 1.6 mm² each

Silicon





3mm

16 + 1 channel UMC 0.18 um chip (layout and picture)

Test Card



Just received ! Very first preliminary results

Two tested chips fully functional

Preamp + Shaper Under Preamp: Gain 8mV/MIP OK Linearity +/-1.5% Dynamic range: 75 MIP OK Noise @ 3.3pF input cap, 3 μ s shaping time: 205 e-140 e- expected Shaper: $2 - 10 \mu s$ tunable peaking time OK Power: Preamp 90 μW $70 \mu W$ expected 110 μW Shaper OK

Linearities



Shaper waveform





Shaper output at 4 us peaking time (8 MIP input)

After these very promising first results, much more tests to be done...

Future

- Complete the present chip tests
- Tests with actual Silicon detectors

Next version will greatly benefit from these thorough series of tests

➔ Submit a 128 channel chip fall '05

Will include:

- ➔ Analog
 - Fast and slow shapers
 - Sparsifier
 - Analog samplers
- ➔ Digital
 - Full ADC
 - Buffering

Follow the trend towards shorter gate lengths: .09μm when available and after .18 μm is fully mastered Jean-Francois Genat, LCWS05, Stanford, March 20th 2005

Conclusion

Deep Sub Micron CMOS technology:

- Allows to implement a highly integrated front-end for SiLC that does not degrade the detector resolution, both in time and amplitude within an affordable power and material budget.

- Allows to implement system integration such as calibration, data compaction, cluster centroid, fast tracking algorithms.

- The present design can be adapted to shorter time shaping to equip shorter strips.

- First Silicon chip in UMC 0.18 μ m CMOS was just received, and is being tested. Very promising first results.

- 128-channel chips including analog sampling, ADC and the digital part for the next version hopefully submitted Fall '05

- Multiplexing up to 512 channels to ADC is foreseen

- SiGe technology considered as a possible competing technology for Jean-Francois Genat, LCWS05, Stanford, March 20th 2005